

**Search Notes**

Application/Control No.

09/708,975

Examiner

Fadey S. Jabr

Applicant(s)/Patent under  
Reexamination

LEON, JP

Art Unit

3639

**SEARCHED**

Class	Subclass	Date	Examiner
705	1, 401- 402, 408, 410	2/28/2006	FSJ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
705	1, 408	2/28/2006	FSJ

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search, see attached	2/28/2006	FSJ
EIC Plus Search, see attached	2/28/2006	FSJ
EIC NPL Search, see attached	2/28/2006	FSJ
Allowance Conference with SPE John Hayes and Primary Examiner Tom Dixon	2/28/2006	FSJ